

Application No.: 10/772,434

2

Docket No.: 333772000800

**AMENDMENTS TO THE SPECIFICATIONS**

Please replace paragraph [0001] with the following amended paragraph:

[0001] This application claims the benefit of application no. 60/447,839, "Method and Structure to Develop a Test Program for Semiconductor Integrated Circuits," filed February 14, 2003; application no. 60/449,622, "Method and Apparatus for Testing Integrated Circuits," filed February 24, 2003; U.S. application no. 10/404,002, "Test emulator, test module emulator, and record medium storing programs therein," filed March 31, 2003; and U.S. application no. 10/403,817, "Test Apparatus and Test Method," filed March 31, 2003, all of which are incorporated herein in their entirety by reference. This application also incorporates by reference in its entirety U.S. application no. [[\_\_\_\_\_]] 10/772,327, "Method and Apparatus for Testing Integrated Circuits," filed concurrently herewith, which claims the benefit of application no. 60/449,622, "Method and Apparatus for Testing Integrated Circuits," filed February 24, 2003.